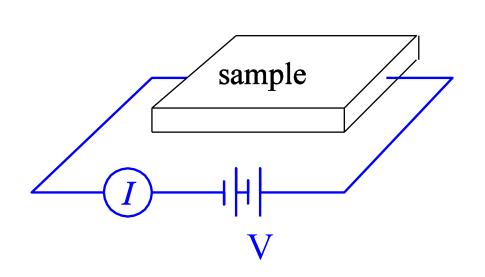
# Quantum transport in nanostructures

About the manifestations of quantum mechanics on the electrical transport properties of conductors



At macro scale

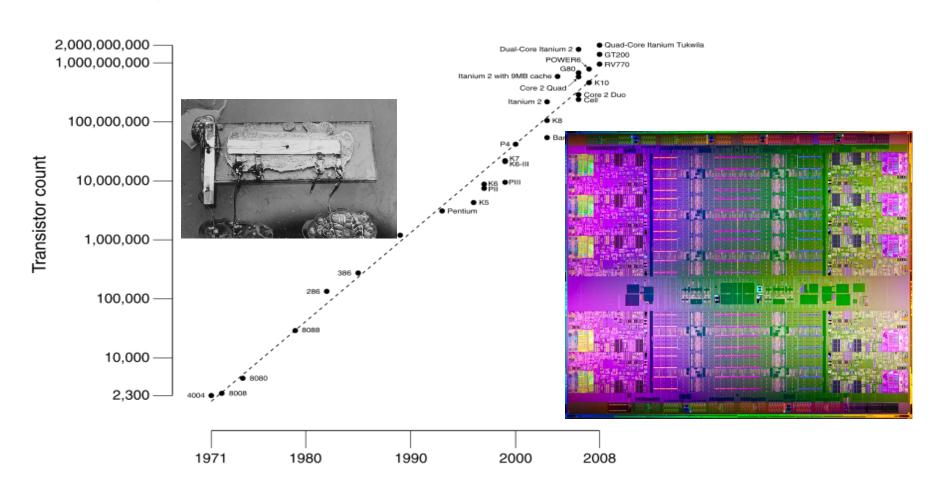
$$I = V/R$$
 (Ohm's law)

$$= \sigma V$$

At nano scale

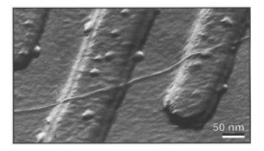
# Moore's Law

The number of transistors per microchip doubles roughly every three years.



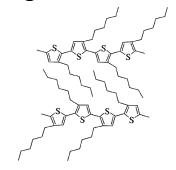
## Nanoscale electronics

#### Nanotubes/wires

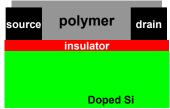


Tans et al. (1997)

### Organic electronics

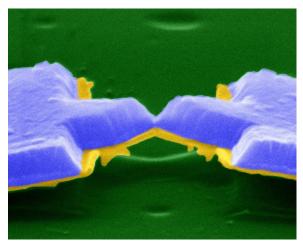


Poly(3-hexylthiophene)

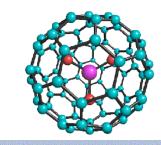


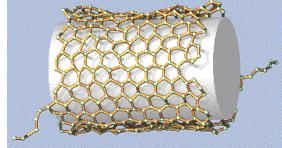
Z.Q. Li et al. (2006)

## Atomic point contacts

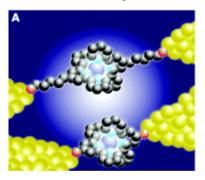


Scheer et al. (1998)



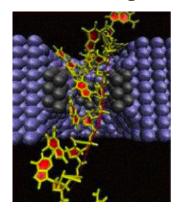


### Molecular junctions



from Nitzan et al. (2003)

### Fast DNA sequencing



Lagerqvist et al. (2006)

## Expected effects for electrons in nanostructures

- Quantum confinement effect
- Tunneling effects
- Charge discreteness and strong electron-electron
   Coulomb interaction effects
- Strong electric field effects
- Ballistic transport effects

# Important mesoscopic regimes

conventional device:		mesoscopic device:	
L>>l <sub>e</sub>	diffusive	L≲l <sub>e</sub>	ballistic
L>>I <sub>φ</sub>	incoherent	L≲I <sub>φ</sub>	phase coherent
L>>λ <sub>F</sub>	no size quantization	L≲ λ <sub>F</sub>	size quantization
e²/C <k<sub>B⊕</k<sub>	no single electron charging	e <sup>2</sup> /C≳ k <sub>B</sub> Θ	single electron charging effects
L>>I <sub>s</sub>	no spin effects	L≲I <sub>s</sub>	spin effects

## Important length scales

Elastic mean free path (l<sub>e</sub>): average distance the electrons travel without being elastically scattered

 $l_e = v_F \tau_e$ .  $v_F$  denotes the Fermi velocity of the electrons

Phase coherent length ( $l_{\Phi}$ ): average distance the electrons travel before their phase is randomized

 $l_{\Phi} = v_F \tau_{\Phi}$ .  $\tau_{\Phi}$  denotes the dephasing time of the electrons

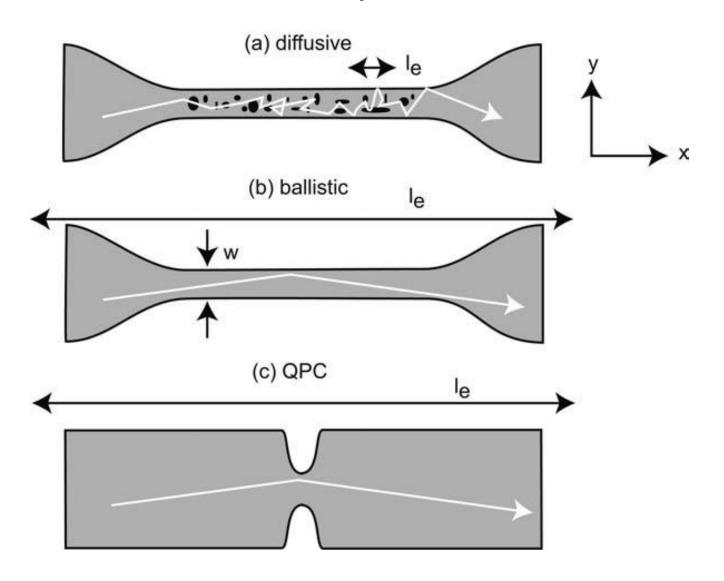
Fermi wavelength ( $\lambda_F$ ): de Broglie wavelength of Fermi electrons

in d = 3: 
$$\lambda_F = 2^{3/2} (\pi/3n)^{1/3}$$

in d = 2: 
$$\lambda_{\rm F} = (2\pi/n)^{1/2}$$

in d = 1: 
$$\lambda_F = 4/n$$

# Quantum wires and point contact



# Typical length scale for mesoscopic regime

Temperature (K) L\* (nm)
4.2 (liquid helium) < 5000
77 (liquid nitrogen) < 100
300 (room temperature) < 10

\*The numbers just give an order of magnitude

## Conduction at the macroscale

- Large number of states contribute to overall current
- Large number of electrons
- Resistivity, mobility, electric field, bias voltage, macrocopic currents are well-defined
- Quantum effects are averaged out by thermal effects

## Conduction at the nanoscale

- Small number of states can affect the overall current
- Wavefunction coherence lengths are comparable to characteristic device dimensions
- Single electrons charging effects can be significant
- These can amount to overall macroscopic electronic properties that show deviations from bulk electronic properties

# **Bolztmann Transport Equation**

Based on the semiclassical transport theory, considering the distributions of carriers to energies and momenta, taking into account scatterings.

The electrons obey the semiclassical equations of motion

$$\mathbf{v}(\mathbf{k}) = (1/\hbar) \nabla_{\mathbf{k}} \varepsilon(\mathbf{k})$$
$$d\mathbf{k}/dt = -e/\hbar (\mathbf{E} + \mathbf{v}(\mathbf{k}) \times \mathbf{B})$$

The general Boltzmann equation to first order approximation:

$$\mathbf{v}(\mathbf{k}) \bullet \nabla \varphi(\mathbf{k}, \mathbf{r}, t) - e\mathbf{E}/\hbar \bullet \nabla_{\mathbf{k}} \varphi(\mathbf{k}, \mathbf{r}, t) + \partial \varphi(\mathbf{k}, \mathbf{r}, t)/\partial t = [\partial \varphi(\mathbf{k}, \mathbf{r}, t)/\partial t]_{scatter}$$

Current density equals to the conductance times electric field

$$j = \sigma E$$

With simplified Bolztmann equation

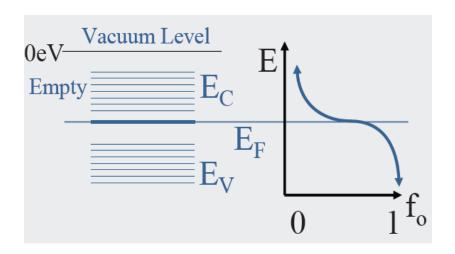
$$\sigma = ne^2 \tau_D/m^* = ne \mu$$

the electron mobility  $\mu \equiv e \, \tau_D^{}/m^*$  .

## Flow of electrons between two reservoirs

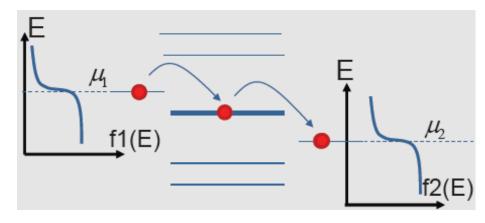
## Electrons obey the Fermi-Dirac distribution

A metal/semiconductor electrode



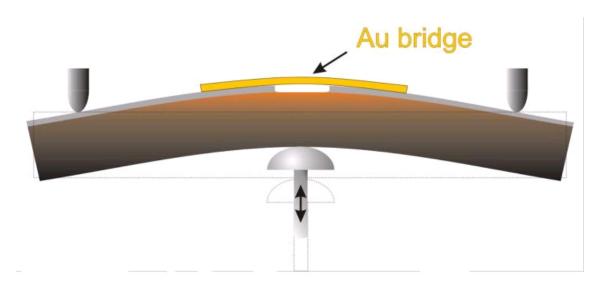
As  $T \sim 0$  K, this is a step function

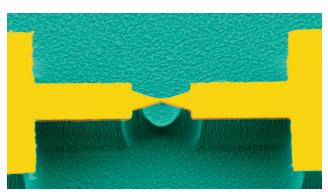
Two electrodes with some other material (states) in between

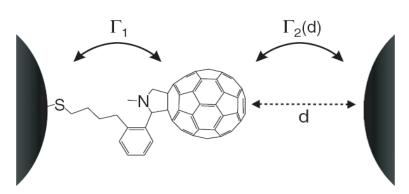


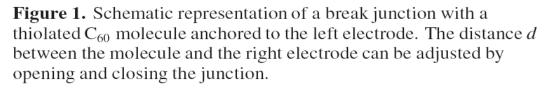
Availability of carriers on the left, and empty slots on the right, how fast the carriers tunnel from the left to the center and how fast the carriers tunnel from the center to the right basically determine the current.

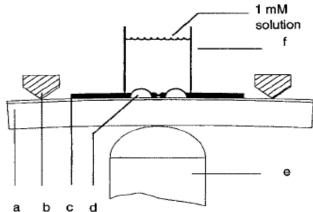
## Molecular Break Junctions







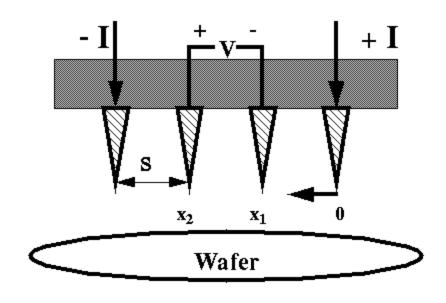




**Fig. 1.** A schematic of the MCB junction with (a) the bending beam, (b) the counter supports, (c) the notched gold wire, (d) the glue contacts, (e) the pizeo element, and (f) the glass tube containing the solution.

# Four point technique

 Make quick measurements of conductivity on novel materials where contacts are not ideal



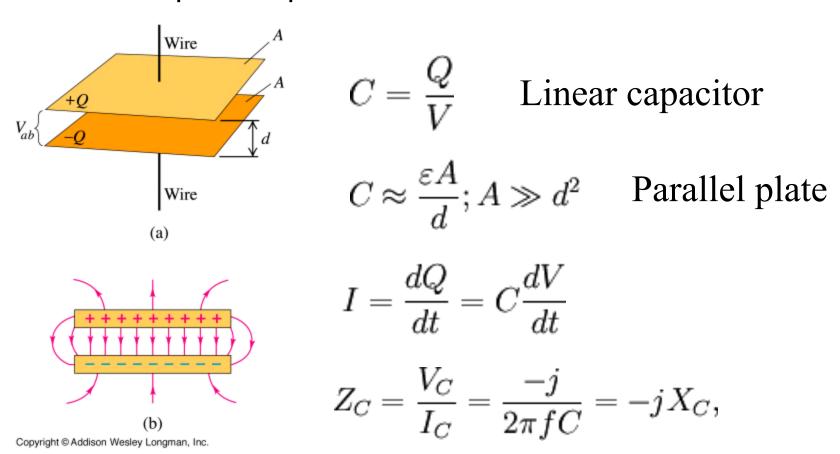
Bulk Sample 
$$\rho = 2\pi s \left(\frac{V}{I}\right)$$
  
t >> s

Thin Sheet 
$$\rho = \frac{\pi t}{ln2} \left( \frac{V}{I} \right)$$
 thickness t << s

Typical probe spacing  $s \sim 1 \text{ mm}$ 

## Capacitance Measurements

## Parallel plate capacitor



Dielectric constant can be measured if the dielectric thickness is known

# Capacitance Spectroscopy

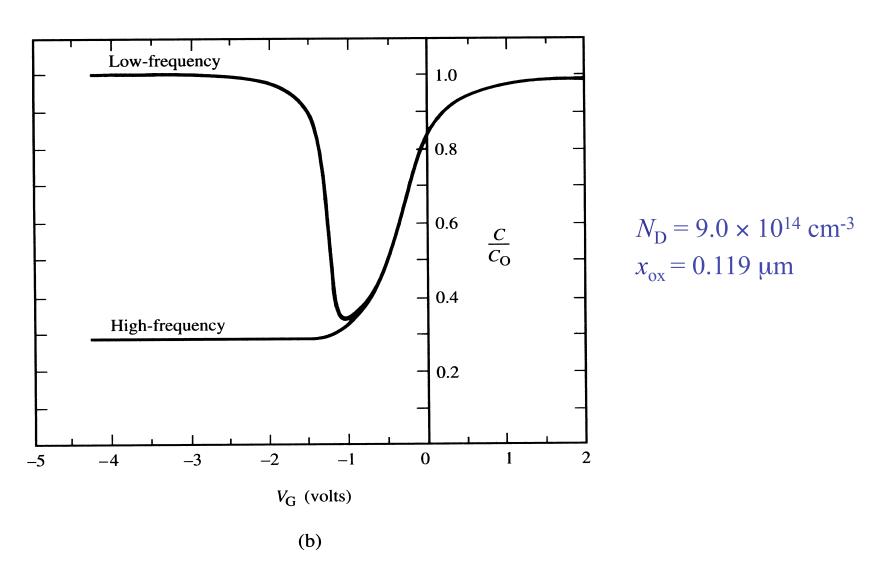
#### When

- semiconductors are used (surface potential and electric field are not linearly dependent)
- the dielectric layer has electric field dependent conductivity (loss)
- There are traps (or states) that can be charged and discharged only at certain voltages
- We can measure the small signal capacitance as a function of DC bias, and interpret C-V curves to gain information about the system

## C-V characterization of MOS structures

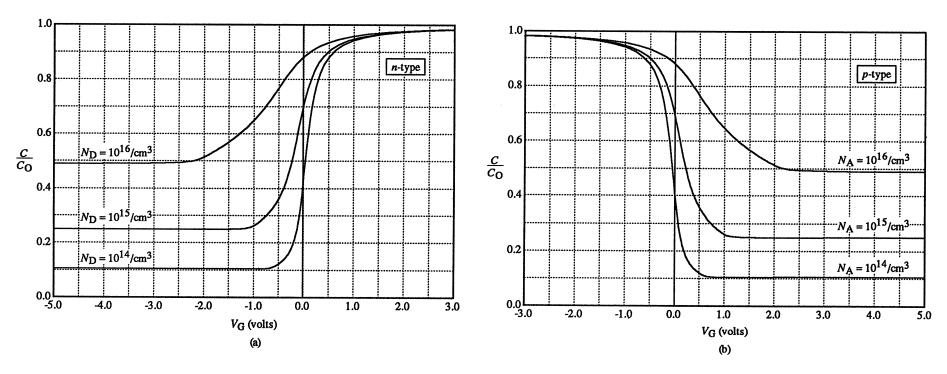
- Measurement of C-V characteristics
  - Apply any dc bias, and superimpose a small (15 mV) ac signal
  - Generally measured at 1 MHz (high frequency) or at variable frequencies between 1KHz to 1 MHz
  - The dc bias V<sub>G</sub> is slowly varied to get quasicontinuous C-V characteristics

# Measured C-V characteristics on an n-type Si



**Figure 16.11** 

# Doping dependence of a MOS capacitor



**Figure 16.14** 

Can tell you carrier concentration, dielectric thickness or constant, Dielectric interface trap densities, Carrier diffusion properties etc.

#### 2-D nanostructures:

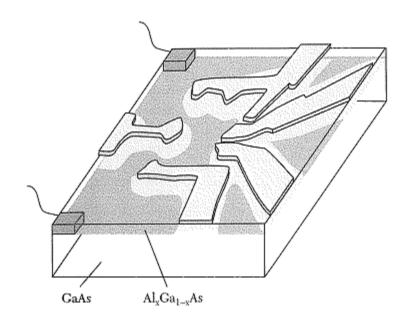
graphene, metallic thin films, superlattices, ....

#### 1-D nanostructures:

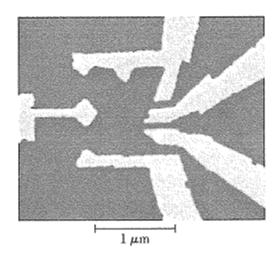
carbon nanotubes, quantum wires, conducting polymers, ....

#### 0-D nanostructures:

semiconductor nanocrystals, metal nanoparticles, lithographically patterned quantum dots, ....

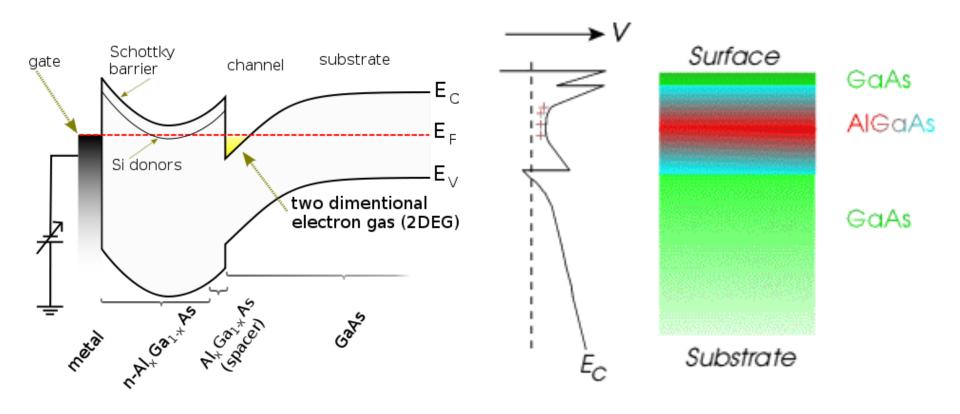


Gate electrode pattern of a quantum dot

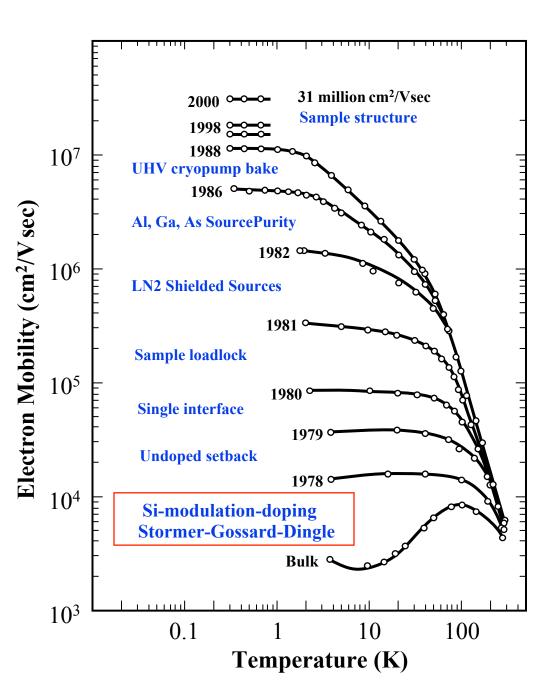


SEM image

# 2D electron gas (2DEG)

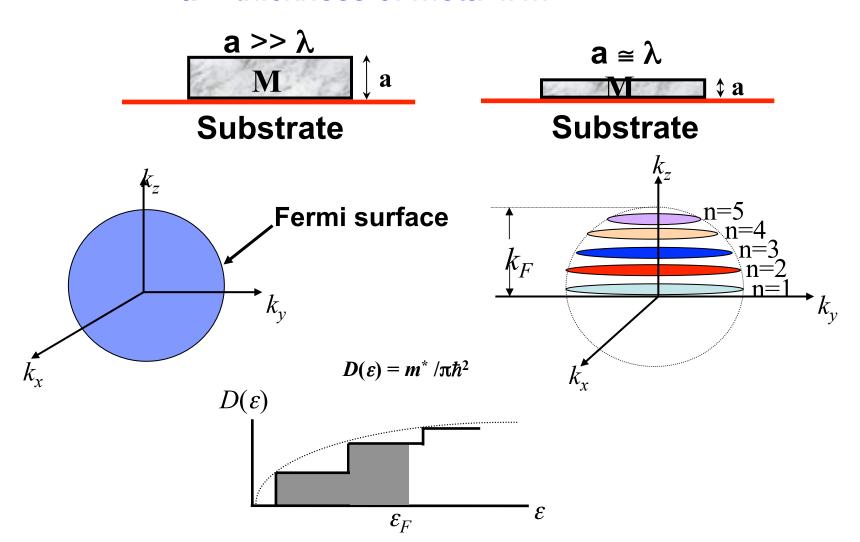


Historical landmarks of 2DEG mobility in GaAs.



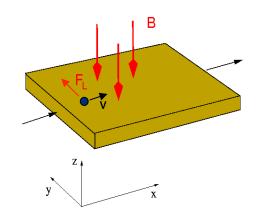
# Electronic Structure of 2-D Systems

 $\lambda$  = de Broglie wavelength of electron **a** = thickness of metal film



# Classical Hall effect (1880 E.H. Hall)





$$m\,\dot{ec{v}} = -eig(ec{E} + ec{v} imes ec{B}ig) = 0 \qquad \Rightarrow \qquad ec{E} = -ec{v} imes ec{B}$$

stationary current:

$$ec{j} = -earrho\,ec{v}$$
  $j_x = rac{earrho}{B}E_y \qquad \qquad j_y = rac{earrho}{B}E_x$ 

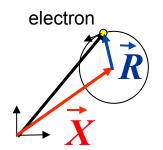
Hall resistance: 
$$R_{xy} \equiv \frac{E_y}{j_x} = \frac{1}{\nu} \frac{2\pi\hbar}{e^2}, \qquad R_{xx} = 0$$

$$rac{1}{
u}=rac{e\,B}{2\pi\hbararrho}=rac{B}{\Phi_Darrho}$$
  $\Phi_D=rac{2\pi\hbar}{e}$  Dirac flux quantum

Hamiltonian: 
$$H=rac{1}{2m}\left[\left(p_x+eA_x
ight)^2+\left(p_y+eA_y
ight)^2
ight]$$

#### coordinate transformation:

$$(x, p_x)$$
  $(y, p_y)$   $\longrightarrow$   $(X, Y)$   $(R_x, R_y)$ 



center of radial vector of cyclotron motion cyclotron motion

$$X = x - R_x$$
  $Y = y - R_y$   $R_x = -\frac{p_y + eA_y}{eB}$   $R_y = \frac{p_x + eA_x}{eB}$ 

#### commutation relations:

$$[X,R_x]=[X,R_y]=[Y,R_x]=[Y,R_y]=0$$
 
$$[X,Y]=-il_m^2 \qquad \qquad [R_x,R_y]=-il_m^2 \qquad \qquad l_m\equiv \sqrt{\frac{\hbar}{eB}}$$

### mapping to oscillator:

$$\hat{a}=rac{1}{\sqrt{2}l_m}ig(R_y-iR_xig) \qquad \hat{b}=rac{1}{\sqrt{2}l_m}ig(X-iYig)$$
  $[\hat{a},\hat{a}^\dagger]=1 \qquad [\hat{b},\hat{b}^\dagger]=1$ 

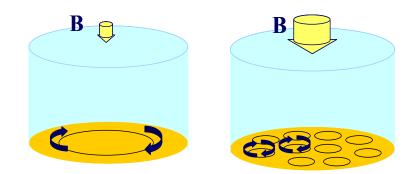
$$H = \hbar \omega_c R^2 / 2 l_m^2 = \hbar \omega_c (a^+ a + \frac{1}{2})$$

## Landau levels

## typical scales:

length

$$\langle R^2 \rangle_n = (1+2n)l_m^2$$



$$l_m \equiv \sqrt{\frac{\hbar}{eB}}$$

 $l_m \equiv \sqrt{\frac{\hbar}{eB}}$  magnetic length

energy

$$\hbar\omega_c=rac{\hbar eB}{m}=rac{l_m^2}{m}$$
 cyclotron frequency

## degeneracy of Landau levels:

center of cyclotron motion (X,Y) arbitrary  $\rightarrow$  degeneracy

2D density of states (DOS)

$$\varrho_{\rm DS} = \frac{1}{2\pi l_m^2} = \frac{eB}{2\pi\hbar} = \frac{B}{\Phi_D}$$

one state per area of cyclotron orbit

filling factor

$$\nu = \frac{\varrho}{\varrho_{\rm DS}} = 2\pi l_m^2 \varrho = \frac{\rho \Phi_D}{B} = \frac{N}{N_\Phi} \qquad \ \ \, \text{\# atoms / \# flux quanta}$$

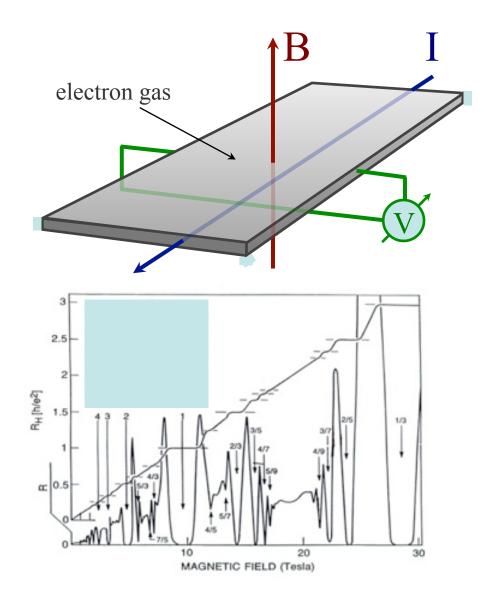
## Quantum Hall effect

Quantization of conductivity for a two-dimensional electron gas at very low temperatures in a high magnetic field.

$$\sigma = \nu \frac{e^2}{h}$$



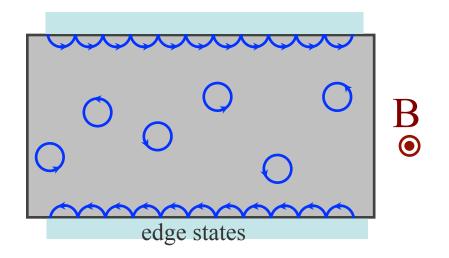
Semiconductor heterostructure confines electron gas to two spatial dimensions.



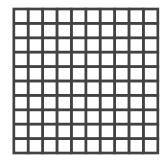
## **Quantum Hall states**

Landau levels

$$E_n = h \frac{eB}{m} \left( n + \frac{1}{2} \right)$$



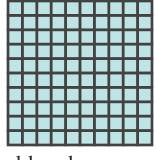
Landau level degeneracy



 $2\Phi/\Phi_0$ 

orbital states

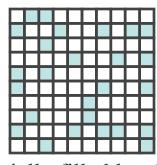
integer quantum Hall



filled level

incompressible liquid

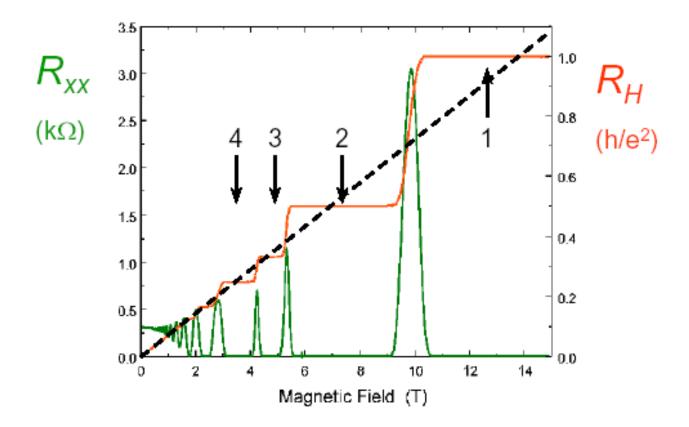
fractional quantum Hall



partially filled level

Coulomb repulsion

incompressible liquid



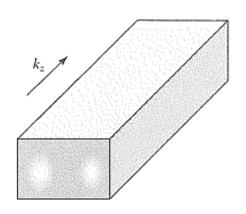
$$R_{\rm H} = (1/\nu)(h/e^2)$$

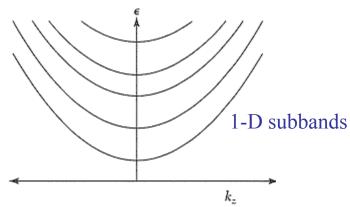
# Electronic Structure of 1-D Systems

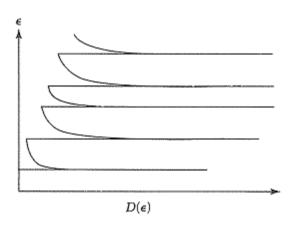
$$\varepsilon = \varepsilon_{i,j} + \frac{\mathrm{h}^2 k^2}{2m}$$

$$\varepsilon = \varepsilon_{i,j} + \frac{h^2 k^2}{2m} \qquad \psi(x,y,z) = \psi_{i,j}(x,y)e^{ikz} \qquad i,j = \text{quantum numbers in the}$$

cross section







$$D(\varepsilon) = \sum_{i,j} D_{i,j}(\varepsilon)$$

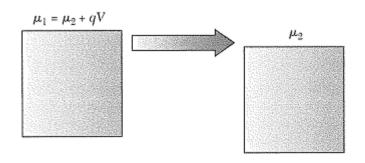
$$D(\varepsilon) = \sum_{i,j} D_{i,j}(\varepsilon) \qquad D_{i,j}(\varepsilon) = \frac{dN_{i,j}}{dk} \frac{dk}{d\varepsilon} = 2 \times 2 \frac{L}{2\pi} \sqrt{\frac{m}{2h^2(\varepsilon - \varepsilon_{i,j})}} = \begin{cases} \frac{4L}{hv_{i,j}} & \varepsilon > \varepsilon_{i,j} \\ 0 & \varepsilon < \varepsilon_{i,j} \end{cases}$$

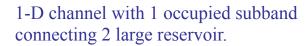
Let there be  $n_{1D}$  carriers per unit length, then  $n_{1D} = \frac{2}{2\pi} 2k_F = \frac{2}{\pi} k_F$ 

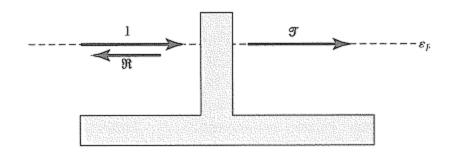
Fermi surface consists of 2 points at  $k = \pm k_F$ 

## Electrical Transport in 1-D

#### Conductance Quantization & the Landauer Formula







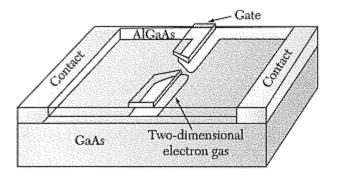
Barrier model for imperfect 1-D channel

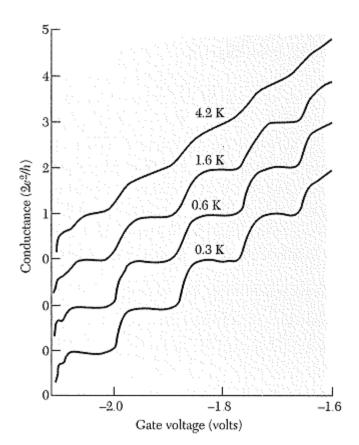
Let  $\Delta n$  be the excess right-moving carrier density,  $D_R(\varepsilon)$  be the corresponding DOS.

$$I = \Delta n \, qv = \frac{D_R(\varepsilon) \, q \, V}{L} \, qv = \frac{2}{hv} \, q^2 V v = \frac{2 \, e^2}{h} \, V \qquad q = \pm e$$

 $\rightarrow$  The conductance quantum  $G_Q = \frac{2 e^2}{h}$  depends only on fundamental constants.

Likewise the resistance quantum  $R_Q = \frac{1}{G_O} = \frac{h}{2 e^2}$ 





If channel is not perfectly conducting,

$$G(\varepsilon_F) = \frac{2e^2}{h} T(\varepsilon_F)$$
 Landauer formula

T = transmission coefficient.

For multi-channel quasi-1-D systems

$$\mathsf{T}\left(\varepsilon_{F}\right) = \sum_{i,j} \; \mathsf{T}_{i,j}\left(\varepsilon_{F}\right)$$

*i*, *j* label transverse eigenstates.

For finite *T*,

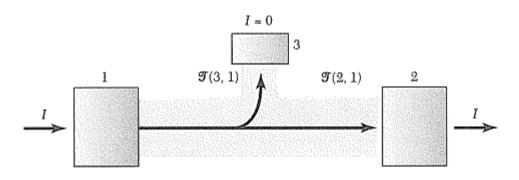
$$I(\varepsilon_{F}, V, T) = \frac{2 e^{2}}{h} \int_{-\infty}^{\infty} d\varepsilon \left[ f_{L}(\varepsilon - eV) - f_{R}(\varepsilon) \right] \mathsf{T}(\varepsilon)$$

$$R = \frac{h}{2 e^2 T} = \frac{h}{2 e^2} \frac{T + (1 - T)}{T} = \frac{h}{2 e^2} + \frac{h}{2 e^2} \frac{R}{T}$$

R = reflection coefficient.

Channel fully depleted of carriers at  $V_g = -2.1 \text{ V}$ .

# Voltage Probes & the Buttiker-Landauer Formulism



 $T^{(n,m)}$  = total transmission probability for an e to go from m to n contact.

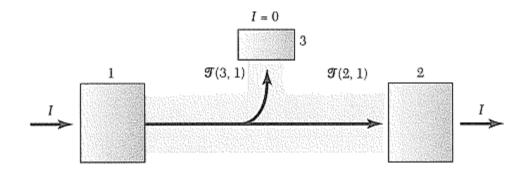
1,2 are current probes; 3 is voltage probe.

For a current probe n with N channels,  $\mu$  of contact is fixed by V.

Net current thru contact is 
$$I_n = \frac{2e^2}{h} \left( N_n V_n - \sum_m \mathsf{T}^{(n,m)} V_m \right)$$
  
Setting  $I_n = 0$ ,  $V_n = V \quad \forall n \quad \rightarrow \quad N_n = \sum_m \mathsf{T}^{(n,m)}$ 

For the voltage probe n,  $V_n$  adjusts itself so that  $I_n = 0$ .

 $I_n$ ,  $V_n$  depend on  $\mathsf{T}^{(n,m)} \to \mathsf{their}$  values are path dependent. Voltage probe can disturb existent paths.



Let every *e* leaving 1 always arrive either at 2 or 3 with no back scattering.

$$V_3 = \frac{\mathsf{T}^{(3,1)} V}{\mathsf{T}^{(3,1)} + \mathsf{T}^{(3,2)}} = \frac{V}{2}$$
 if  $\mathsf{T}^{(3,1)} = \mathsf{T}^{(3,2)}$ 

Current out of 1: 
$$I = \frac{2e^2}{h} \left( V - \mathsf{T}^{(1,3)} V_3 \right) = \frac{2e^2}{h} V \left( 1 - \frac{1}{2} \mathsf{T}^{(1,3)} \right) < \frac{2e^2}{h} V$$
 no probe

Mesoscopic regime:  $l_e < L < l_{\omega}$ .

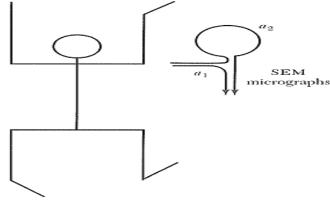
$$t^{(m,n)} \propto \sum_{j} a_{j} \exp \left[ \frac{i}{h} \int_{l}^{m} \left( \mathbf{p} - \frac{e}{c} \mathbf{A} \right) \cdot d\mathbf{l} \right]$$

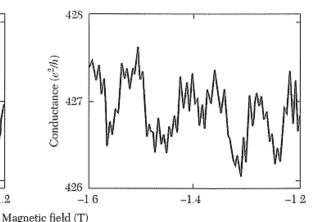
$$\mathsf{T}^{(n,m)} = \left| t^{(m,n)} \right|^2$$

Conductance (e<sup>2</sup>/h)

505

-1.6





#### Aharonov-Bohm effect

$$\int_{loop} \mathbf{A} \cdot d\mathbf{l} = \int_{S} \nabla \times \mathbf{A} \cdot dS = \Phi$$

$$a_1 + a_2 \exp \left[ \frac{ie}{hc} \int_{loop} \mathbf{A} \cdot d\mathbf{l} \right]$$

-1.2

-1.4

$$\left| a_1 + a_2 \exp \left[ \frac{ie}{hc} \int_{loop} \mathbf{A} \cdot d\mathbf{l} \right] \right|^2 = \left| a_1 \right|^2 + \left| a_2 \right|^2 + 2\left| a_1 \right| \left| a_2 \right| \cos \left( \frac{2\pi \Phi}{hc/e} \right)$$

$$\Phi_0 = \frac{hc}{e}$$

#### Localization

$$T = \frac{|t_1|^2 |t_2|^2}{1 - 2|r_1| |r_2| \cos \varphi^* + |r_1|^2 |r_2|^2} \longrightarrow R = \frac{h}{2 e^2 T} = \frac{h}{2 e^2} \frac{1 - 2|r_1| |r_2| \cos \varphi^* + |r_1|^2 |r_2|^2}{|t_1|^2 |t_2|^2}$$

 $\langle \dots \rangle$  = average over  $\varphi^*$  = average over k or  $\varepsilon$ .

$$\langle R \rangle = \frac{h}{2e^2} \frac{1 + |r_1|^2 |r_2|^2 - 2|r_1| |r_2| \langle \cos \varphi^* \rangle}{|t_1|^2 |t_2|^2} = \frac{h}{2e^2} \frac{1 + |r_1|^2 |r_2|^2}{|t_1|^2 |t_2|^2} \qquad \text{larger than incoherent limit} \qquad \frac{h}{2e^2} \frac{1 - |r_1|^2 |r_2|^2}{|t_1|^2 |t_2|^2}$$

Consider a long conductor consisting of a series of elastic scatterers of scattering length  $l_e$ .

$$\langle R + dR \rangle = \langle R \rangle \left( 1 + 2 \frac{dL}{l_e} \right) \rightarrow \langle dR \rangle = \langle R \rangle \frac{2dL}{l_e}$$

$$\therefore \quad \ln \frac{\langle R \rangle}{\langle R \rangle_0} = \frac{2L}{l_e} \quad \text{where} \quad \langle R \rangle_0 = \langle R \rangle \Big|_{L=0} = R_Q = \frac{h}{2e^2}$$

$$\langle R \rangle = \frac{h}{2e^2} \exp \left( \frac{2L}{l_e} \right) \quad \text{C.f. Ohm's law } R \propto L$$

For a 1-D system with disorder, all states become localized to some length  $\xi$ . Absence of extended states  $\to R \propto \exp(a L/\xi)$ , a = some constant. For quasi-1-D systems, one finds  $\xi \sim N l_e$ , where N = number of occupied subbands.

For T > 0, interactions with phonons or other *e*'s reduce phase coherence to length  $l_{\varphi} = A T$ 

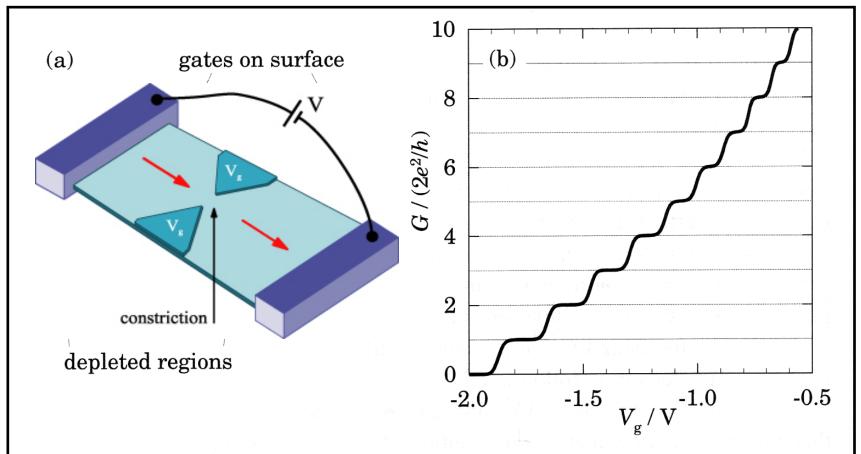
$$\therefore \qquad \langle R \rangle \approx \frac{h}{2e^2} \exp\left(\frac{2l_{\varphi}}{l_e}\right) \qquad \text{for each coherent segment.}$$

Overall  $\langle R \rangle \approx$  incoherent addition of  $L/l_{\varphi}$  such segments.

For sufficiently high T,  $l_{\varphi} \leq l_{e}$ , coherence is effectively destroyed & ohmic law is recovered.

All states in disordered 2-D systems are also localized. Only some states (near band edges) in disordered 3-D systems are localized.

# Conductance of a quantum point contact



**FIGURE 5.22.** (a) Layout of a typical quantum point contact, a short constriction defined by patterned metal gates on the surface of a heterostructure containing a 2DEG. (b) Calculated conductance  $G(V_g)$  as a function of gate voltage  $V_g$ . [From Nixon, Davies, and Baranger (1991).]

# Quantum point contact

GaAs/AlGaAs interface: two-dimensional electron gas

# Quantum conductance

$$G = G_0 n$$
  
 $G_0 = \frac{2e^2}{h} = 7.75 \times 10^{-5} \Omega^{-1}$   
 $n = 1, 2, 3 \cdots$ 

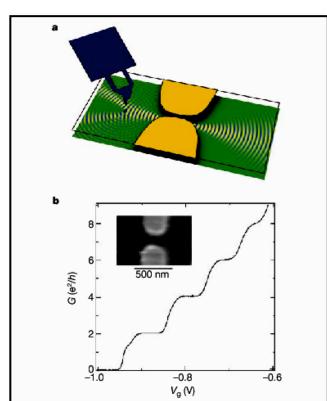
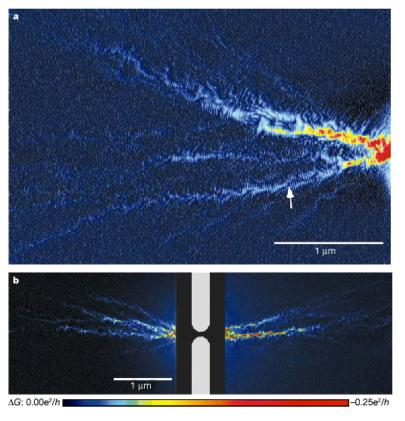


Figure 1 Experimental set-up. a, Schematic diagram of the experimental set-up used for imaging electron flow. The tip introduces a movable depletion region which scatters electron waves flowing from the quantum point contact (QPC). An image of electron flow is obtained by measuring the effect the tip has on QPC conductance as a function of tip position. Two ohmic contacts ~1 mm away from the QPC (not shown) allow the conductance of the QPC to be measured using an a.c. lock-in amplifier at 11 kHz. The root-mean-square voltage across the QPC, 0.2 mV, was chosen in order not to heat electrons significantly above the lattice temperature of 1.7 K, b, Conductance of the QPC used for Fig. 2b versus QPC width controlled by the gate voltage. Steps at integer multiples of 2e<sup>2</sup>/h are clearly visible. The inset is a topographic AFM image of the QPC.

# Electron flow close to a quantum point contact



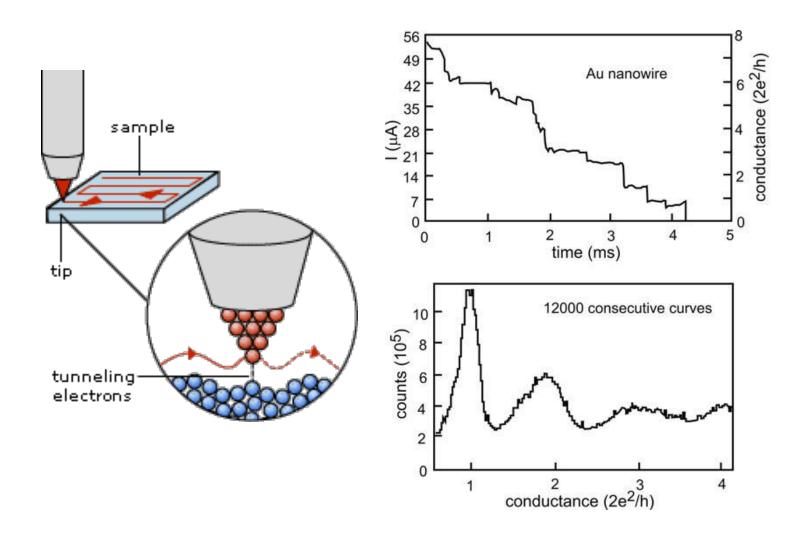
- Electrons are wave with wave vector  $k_F$
- Interference stripewith

$$\lambda = \frac{1}{2k_F}$$

Figure 2 Experimental images of electron flow. **a**, Image of electron flow from one side of a QPC at T = 1.7 K, biased on the  $G = 2e^2/h$  conductance step. Dark regions correspond to areas where the tip had little effect on QPC conductance, and hence are areas of low electron flow. The colour varies and the height in the scan increases with increasing electron flow. Narrow branching channels of electron flow are visible, and fringes spaced

by  $\lambda_f/2$ , half the Fermi wavelength, are seen to persist across the entire scan. **b**, Images of electron flow from both sides of a different QPC, again biased on the  $G=2e^2/h$  conductance step. The gated region in the centre was not scanned. Strong channelling and branching are again clearly visible. The white arrow points out one example of the formation of a cusp downstream from a dip in the potential.

# Quantum point contact formed in STM



# Electronic Structure of 0-D Systems

Quantum dots: Quantized energy levels.

*e* in spherical potential well:  $\varepsilon_{n,l,m} = \varepsilon_{n,l}$   $\psi_{n,l,m}(r,\theta,\phi) = R_{n,l}(r) Y_{l,m}(\theta,\phi)$ 

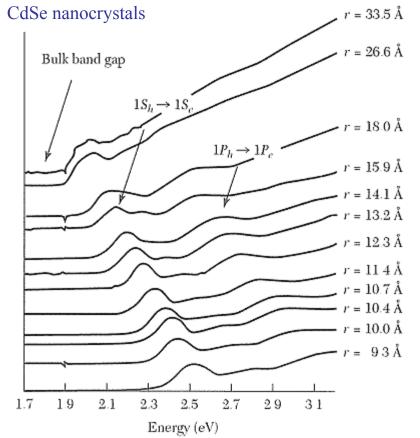
For an infinite well with V = 0 for r < R:

$$\varepsilon_{n,l} = \frac{h^2 \beta_{n,l}^2}{2m * R^2} \qquad R_{n,l}(r) = j_l \left(\frac{\beta_{n,l} r}{R}\right) \qquad \text{for } r < R$$

$$\beta_{n,l} = n^{\text{th root of } j_l(x)}. \qquad j_l(\beta_{n,l}) = 0$$

$$\beta_{0,0} = \pi$$
 (1S),  $\beta_{0,1} = 4.5$  (1P),  $\beta_{0,2} = 5.8$  (1D)  $\beta_{1,0} = 2\pi$  (2S),  $\beta_{1,1} = 7.7$  (2P)

# Semiconductor Nanocrystals



For CdSe:

$$m_c^* = 0.13 m$$
 
$$\varepsilon_{n,l} = \left(\frac{\beta_{n,l}}{\beta_{0,0}}\right)^2 \left(\frac{2.9eV}{R^2}\right)$$

For 
$$R = 2 \text{ nm}$$
,  $\varepsilon_{0,1} - \varepsilon_{0,0} = 0.76 \text{ eV}$ 

For e,  $\varepsilon_{0,0}$  increases as R decreases. For h,  $\varepsilon_{0,0}$  decreases as R decreases.  $\rightarrow E_g$  increases as R decreases.

Optical spectra of nanocrystals can be tuned continuously in visible region.

Applications: fluorescent labeling, LED.

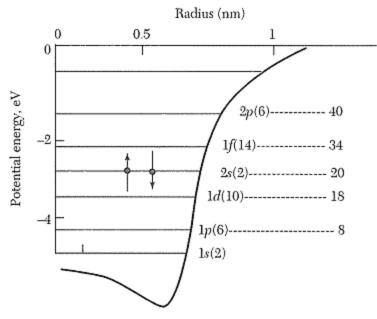
Kramers-Kronig relation:

$$\sigma''(\omega) = -\frac{2\omega}{\pi} P \int_{0}^{\infty} \frac{\sigma'(s)}{s^{2} - \omega^{2}} ds$$

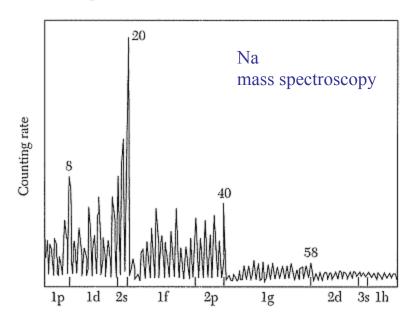
For 
$$\omega \to \infty$$
  $\sigma''(\omega) \approx \frac{ne^2}{m\omega} \approx \frac{2}{\pi \omega} \int_0^\infty \sigma'(s) ds \to \int_0^\infty \sigma'(s) ds = \frac{\pi n e^2}{2m}$  same as bulk

Strong transition at some  $\omega$  in quantum dots  $\rightarrow$  laser?

#### **Metallic Dots**



Small spherical alkali metallic cluster



Mass spectroscopy (abundance spectra): Large abundance at cluster size of magic numbers (8, 20, 40, 58, ...)

 $\rightarrow$  enhanced stability for filled *e*-shells.

Average level spacing at  $\varepsilon_F$ :

$$\Delta \varepsilon \approx \frac{1}{D(\varepsilon_F)} = \frac{2\varepsilon_F}{3N}$$

For Au nanoparticles with R = 2 nm,  $\Delta \varepsilon \approx 2$  meV.

whereas CdSe gives  $\Delta \varepsilon \approx 0.76$  eV.

 $\rightarrow \epsilon$  quantization more influential in semiconductor.

Optical properties of metallic dots dominated by surface plasmon resonance.

If retardation effects are negligible,  $P = \frac{\chi}{1 + \frac{4\pi}{3} \chi} E_{ext}$ 

$$\chi(\omega) = -\frac{n e^2}{m \omega^2} \longrightarrow P = \frac{1}{\frac{m \omega^2}{n e^2} - \frac{4\pi}{3}} E_{ext} = \frac{3}{4\pi \left(\frac{3 \omega^2}{\omega_p^2} - 1\right)} E_{ext}$$

Surface plasma mode at singularity:  $\omega_{sp} = \frac{\omega_p}{\sqrt{3}}$  indep of R.

For Au or Ag,  $\omega_p \sim UV$ ,  $\omega_{sp} \sim Visible$ .

→ liquid / glass containing metallic nanoparticles are brilliantly colored.

Large E just outside nanoparticles near resonance enhances weak optical processes. This is made use of in Surface Enhanced Raman Scattering (SERS), & Second Harmonic Generation (SHG).

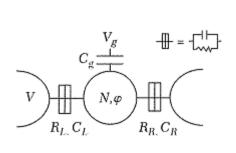
# Discrete Charge States

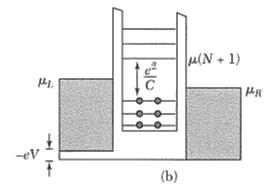
Thomas-Fermi approximation:

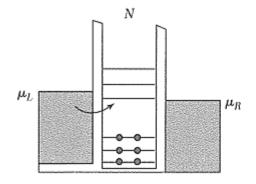
$$\mu_{N+1} = \varepsilon_{N+1} - e \varphi = \varepsilon_{N+1} + NU - \alpha e V_g$$

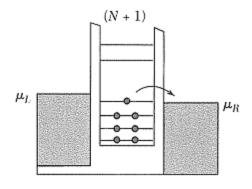
U = interaction between 2 e's on the dot = charging energy.

 $\alpha$  = rate at which a nearby gate voltage  $V_g$  shifts  $\varphi$  of the dot.









Neglecting its dependence on state,

$$U = \frac{e^2}{C} \qquad \alpha = \frac{C_g}{C}$$

C =capacitance of dot.

 $C_g$  = capacitance between gate & dot

If dot is in weak contact with reservoir, e's will tunnel into it until the  $\mu$ 's are equalized.

Change in  $V_g$  required to add an e is

$$\Delta V_g = \frac{1}{\alpha e} \left( \varepsilon_{N+1} - \varepsilon_N + \frac{e^2}{C} \right)$$

U depends on size &shape of dot & its local environment.

For a spherical dot of radius R surrounded by a spherical metal shell of radius R + d,

$$U = \frac{e^2}{\varepsilon R} \frac{d}{R + d}$$

For R = 2 nm, d = 1 nm &  $\varepsilon = 1$ , we have  $U = 0.24 \text{ eV} >> k_B T = 0.026 \text{eV}$  at T = 300 K

→ Thermal fluctuation strongly supressed.

For metallic dots of 2nm radius,  $\Delta \varepsilon \approx 2 \text{meV} \rightarrow \Delta V_g$  due mostly to U. For semiC dots, e.g., CdSe,  $\Delta \varepsilon \approx 0.76 \text{ eV} \rightarrow \Delta V_g$  due both to  $\Delta \varepsilon \& U$ .

Charging effect is destroyed if tunneling rate is too great. Charge resides in dot for time  $\delta t \approx RC$ . (R = resistance)

$$\rightarrow \delta \varepsilon \approx \frac{h}{\delta t} \approx \frac{h}{RC} = \frac{e^2}{C} \frac{h}{e^2} \frac{1}{R}$$

Quantum fluctuation smears out charging effect when  $\delta \varepsilon \approx U$ , i.e., when  $R \sim h / e^2$ .

#### Conditions for a Coulomb Blockade

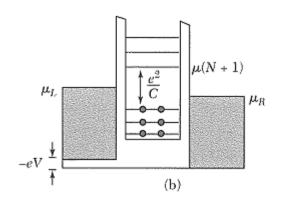
1) The Coulomb energy  $e^2/C$  needs to exceed the thermal energy  $k_BT$ .

Otherwise an extra electron can get onto the dot with thermal energy instead of being blocked by the Coulomb energy. A dot needs to be either small (<10 nm at 300K) or cold (< 1K for a  $\mu$ m sized dot).

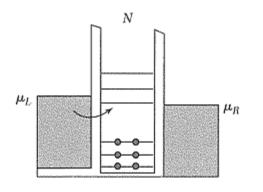
2) The residence time  $\Delta t$ =RC of an electron on the dot needs to be so long that the corresponding energy uncertainty  $\Delta E = h/\Delta t = h/RC$  is less than the Coulomb energy  $e^2/C$ . That leads to a condition for the tunnel resistance between the dot and source /drain:  $R > h/e^2 \approx 26 \text{ k}\Omega$ 

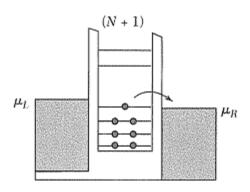
# Electrical Transport in 0-D

For  $T < (U + \Delta \varepsilon) / k_B$ ,  $U \& \Delta \varepsilon$  control e flow thru dot.



Transport thru dot is suppressed when  $\mu_L \& \mu_R$  of leads lie between  $\mu_N \& \mu_{N+1}$  (Coulomb blockade)

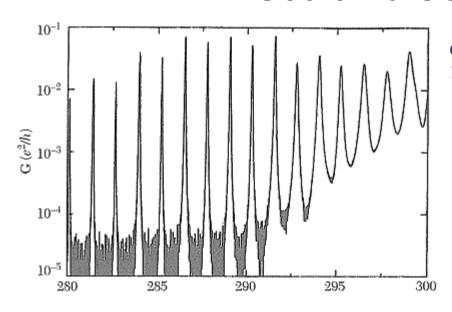




Transport is possible only when  $\mu_{N+1}$  lies between  $\mu_L \& \mu_R$ .

 $\rightarrow$  Coulomb oscillations of  $G(V_g)$ .

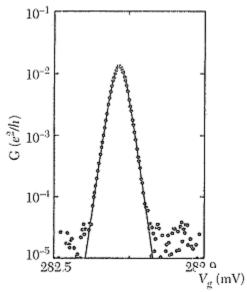
#### **Coulomb Oscillations**

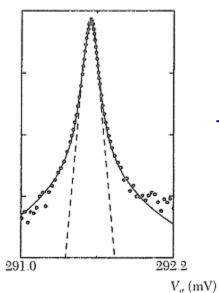


GaAs/AlGaAsT = 0.1K

$$\Delta V_g = \frac{1}{\alpha e} \left( \varepsilon_{N+1} - \varepsilon_N + \frac{e^2}{C} \right)$$

Coulomb oscillation occurs whenever  $U > k_B T$ , irregardless of  $\Delta \varepsilon$ .





For  $\Delta \varepsilon >> k_B T$ , c.f. resonant tunneling:

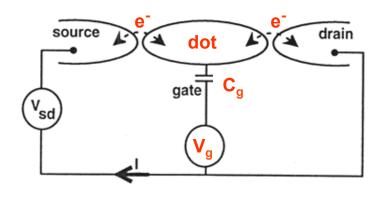
$$T = \frac{|t_1|^2 |t_2|^2}{1 - 2|r_1| |r_2| \cos(2kL + \varphi_{r_1} + \varphi_{r_2}) + |r_1|^2 |r_2|^2}$$

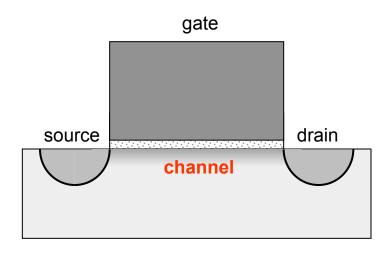
$$T\left(\varepsilon\right) = \frac{4\Gamma_{1}\Gamma_{2}}{\left(\Gamma_{1} + \Gamma_{2}\right)^{2} + 4\left(\varepsilon - \varepsilon_{n}\right)^{2}}$$

Thermal broadening

Breit-Wigner lineshape

#### Single Electron Transistor (SET)





A single electron transistor is similar to a normal transistor (below), except

- 1) the channel is replaced by a small dot.
- 2) the dot is separated from source and drain by thin insulators.

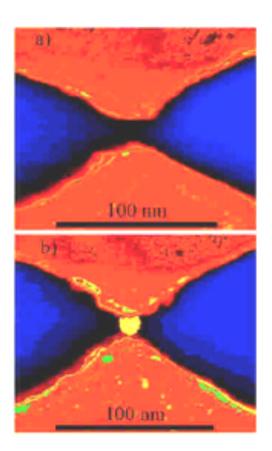
An electron tunnels in two steps:

The gate voltage  $V_g$  is used to control the charge on the gate-dot capacitor  $C_q$ .

How can the charge be controlled with the precision of a single electron?

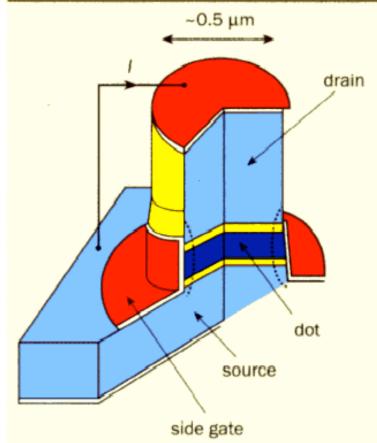
Kouwenhoven et al., Few Electron Quantum Dots, Rep. Prog. Phys. **64**, 701 (2001).

# Designs for Single Electron Transistors



Nanoparticle attracted electrostatically to the gap between source and drain electrodes. The gate is underneath.

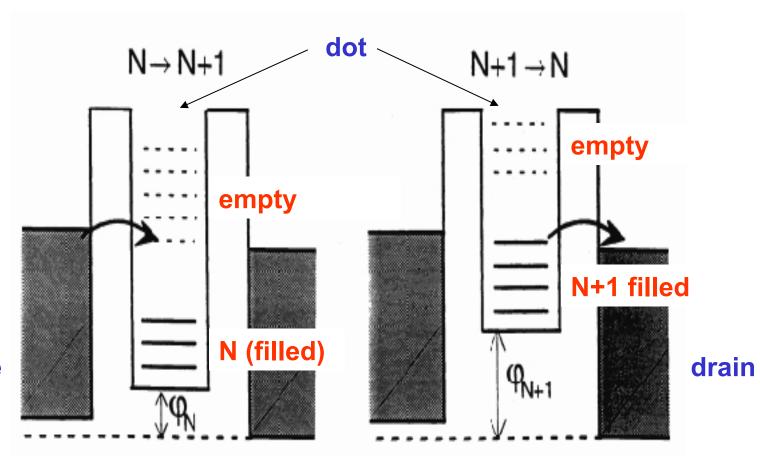
#### 1 Vertical quantum dot structure



The quantum-dot structure studied at Delft and NTT in Japan is fabricated in the shape of a round pillar. The source and drain are doped semiconductor layers that conduct electricity, and are separated from the quantum dot by tunnel barriers 10 nm thick. When a negative voltage is applied to the metal side gate around the pillar, it reduces the diameter of the dot from about 500 nm to zero, causing electrons to leave the dot one at a time.

#### Two Step Tunneling

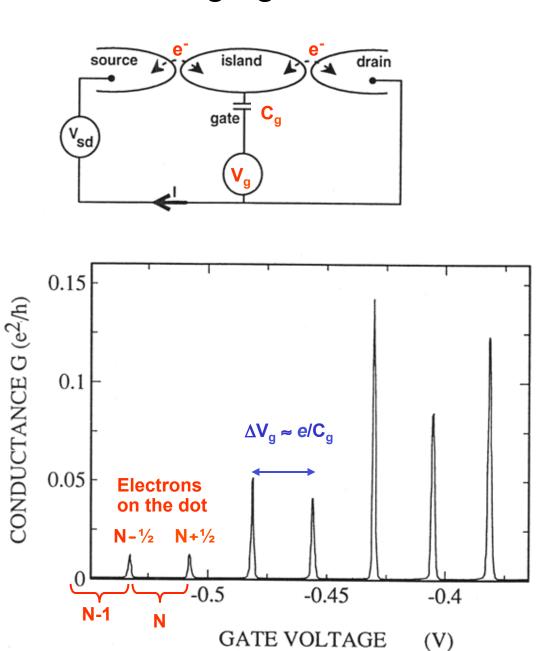
source → dot → drain



source

(For a detailed explanation see the annotation in the .ppt version.)

# Charging a Dot, One Electron at a Time



Sweeping the gate voltage  $V_g$  changes the charge  $Q_g$  on the gate-dot capacitor  $C_g$ . To add one electron requires the voltage  $\Delta V_q \approx e/C_g$  since  $C_g = Q_g/V_g$ .

The source-drain conductance **G** is zero for most gate voltages, because putting even one extra electron onto the dot would cost too much Coulomb energy. This is called Coulomb blockade.

Electrons can hop onto the dot only at a gate voltage where the number of electrons on the dot flip-flops between N and N+1. Their time-averaged number is N+½ in that case.

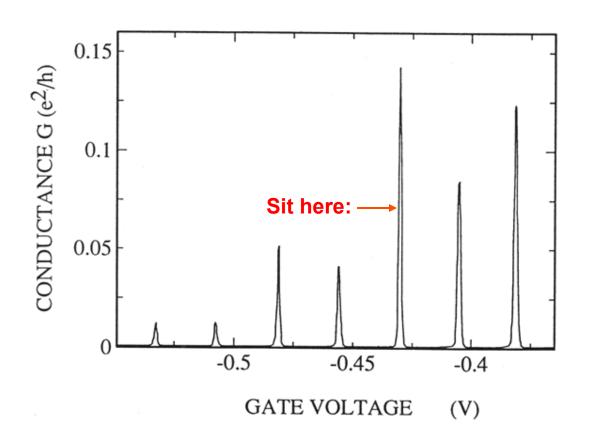
The spacing between these half -integer conductance peaks is an integer.

#### The SET as Extremely Sensitive Charge Detector

At low temperature, the conductance peaks in a SET become very sharp.

Consequently, a very small change in the gate voltage half-way up a peak produces a large current change, i.e. a large amplification. That makes the SET extremely sensitive to tiny charges.

The flip side of this sensitivity is that a SET detects every nearby electron. When it hops from one trap to another, the SET produces a noise peak.

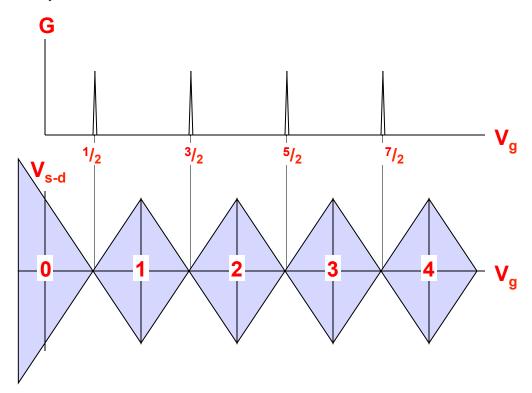


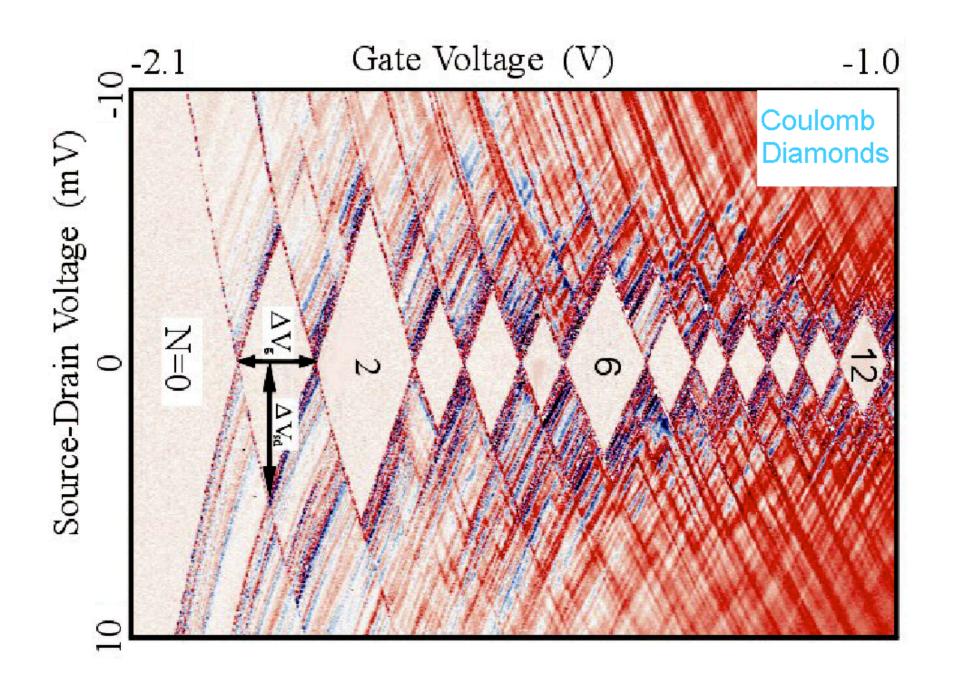
#### Gate Voltage versus Source-Drain Voltage

The situation gets a bit confusing, because there are two voltages that can be varied, the gate voltage  $V_q$  and the source-drain voltage  $V_{s-d}$ .

Both affect the conductance. Therefore, one often plots the conductance G against both voltages (see the next slide for data).

Schematically, one obtains "Coulomb diamonds", which are regions with a stable electron number N on the dot (and consequently zero conductance).



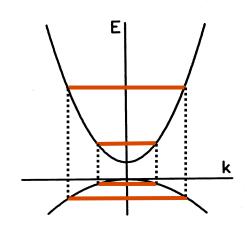


#### Including the Energy Levels of a Quantum Dot

Contrary to the Coulomb blockade model, the data show Coulomb diamonds with uneven size. Some electron numbers have particularly large diamonds, indicating that the corresponding electron number is particularly stable.

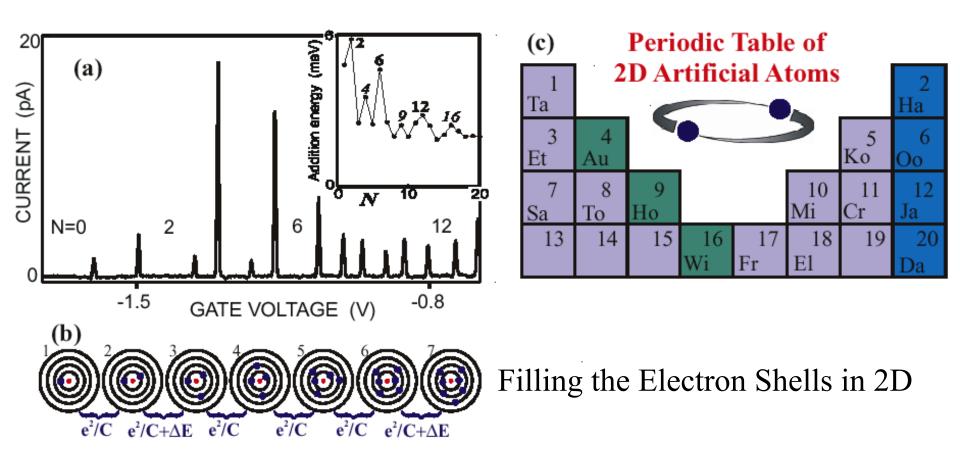
This is reminiscent of the closed electron shells in atoms. Small dots behave like artificial atoms when their size shrinks down to the electron wavelength.

Continuous energy bands become quantized (see Lecture 8). Adding one electron requires the Coulomb energy U plus the difference  $\Delta E$  between two quantum levels (next slide). If a second electron is added to the same quantum level (the same shell in an atom),  $\Delta E$  vanishes and only the Coulomb energy U is needed.



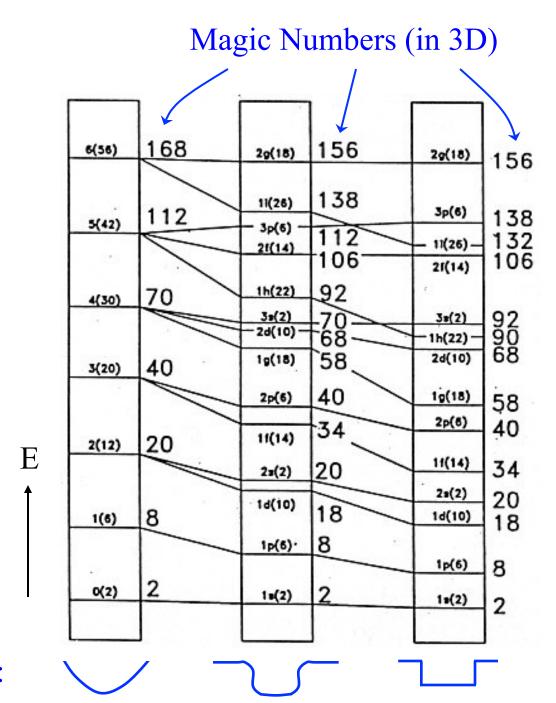
The quantum energy levels can be extracted from the spacing between the conductance peaks by subtracting the Coulomb energy  $U = e^2/C$ .

#### Quantum Dot in 2D (Disk)



**Figure 2.** Current flowing through a 2D circular quantum dot when varying the gate voltage. (a) The first peak marks the voltage where the  $1^{st}$  electron enters the dot, and the number of electrons, N, increases by one at each subsequent peak. The distance between adjacent peaks corresponds to the addition energies (see inset). (b) The addition of electrons to circular orbits is shown schematically. The first shell can hold 2 electrons whereas the second shell can contain up to 4 electrons. It therefore costs extra energy to add the  $3^{rd}$  and  $7^{th}$  electron. (c) The electronic properties following from a 2D shell structure can be summarized in a periodic table for 2 D elements. (The elements are named after team members from NTT and Delft.)

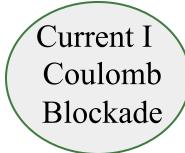
Shell Structure of Energy Levels for Various Potentials



**Potentials:** 

# Precision Standards from "Single" Electronics

Count individual electrons, pairs, flux quanta



$$I = e f$$

Voltage V Josephson Effect

$$V = h/2e \cdot f$$

$$V/I = R = h/e^2$$

Resistance R
Quantum
Hall Effect

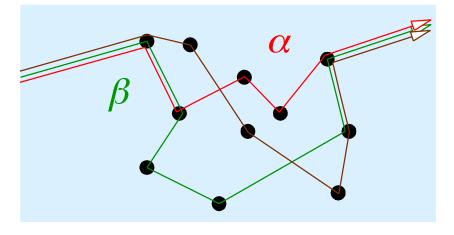
# Quantum interference

$$g = \sum_{m,n} |t_{nm}|^{2}$$

$$= \sum_{m,n} \sum_{\alpha} |t_{nm,\alpha}|^{2} + \sum_{m,n} \sum_{\alpha \neq \beta} t_{nm,\alpha} (t_{nm,\beta})^{*}$$

$$= g_{\text{class}} + \delta g$$
sample

In general:  $\delta g$  small, random sign



 $t_{nm,\alpha}$ ,  $t_{nm,\beta}$ : amplitude for transmission along paths  $\alpha$ ,  $\beta$ 

#### Quantum interference

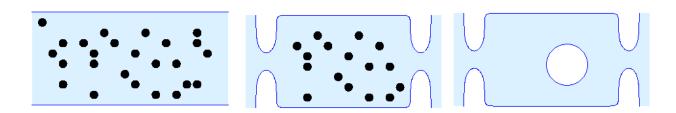
$$g = \sum_{m,n} |t_{nm}|^{2}$$

$$= \sum_{m,n} \sum_{\alpha} |t_{nm,\alpha}|^{2} + \sum_{m,n} \sum_{\alpha \neq \beta} t_{nm,\alpha} (t_{nm,\beta})^{*}$$

$$= g_{\text{class}} + \delta g$$
sample

Three prototypical examples:

- Disordered wire
- Disordered quantum dot
- Ballistic quantum dot



# Scattering matrix and Green function

Recall: retarded Green function is solution of

$$(arepsilon-\mathcal{H})\mathcal{G}^{\mathrm{R}}(\mathbf{r},\mathbf{r}';\omega)=\delta(\mathbf{r}-\mathbf{r}'),$$

In one dimension:

$$\mathcal{G}^{\mathrm{R}}(x,x';arepsilon) = -rac{i}{\hbar v}e^{ik|x-x'|},$$

Green function in channel basis:

$$\varepsilon_k = \varepsilon$$
 and  $v = \hbar^{-1} d\varepsilon_k / dk$ 

$$\mathcal{G}^{\mathrm{R}}(\mathbf{r}, \mathbf{r}'; \varepsilon) = \sum_{m=1}^{N_j} \sum_{n=1}^{N_k} \mathcal{G}^{\mathrm{R}}_{m,j;n,k}(x, x'; \varepsilon) \chi_{m,j}(y) \chi_{n,k}(y').$$

r in lead j; r' in lead k

Substitute 1d form of Green function

$$\mathcal{G}_{mn}^{R}(x,x') = -\frac{i}{\hbar v_m} \delta_{mn} \delta_{jk} e^{ik_m|x-x'|} - \frac{i}{\hbar (v_m v_n)^{1/2}} S_{m,j;n,k} e^{ik_m|x|+ik_n|x'|}.$$

If 
$$j \neq k$$
:  $S_{m,j;n,k} = i\hbar (v_m v_n)^{1/2} \mathcal{G}_{m,k;n,k}^{\mathrm{R}}(0,0,\varepsilon)$   
=  $i\hbar (v_m v_n)^{1/2} \int dy \int dy' \chi_{m,j}(y) \chi_{n,k}(y') \mathcal{G}^{\mathrm{R}}(\mathbf{r},\mathbf{r}';\varepsilon)$ 

# Aharonov-Bohm (A-B) Effect

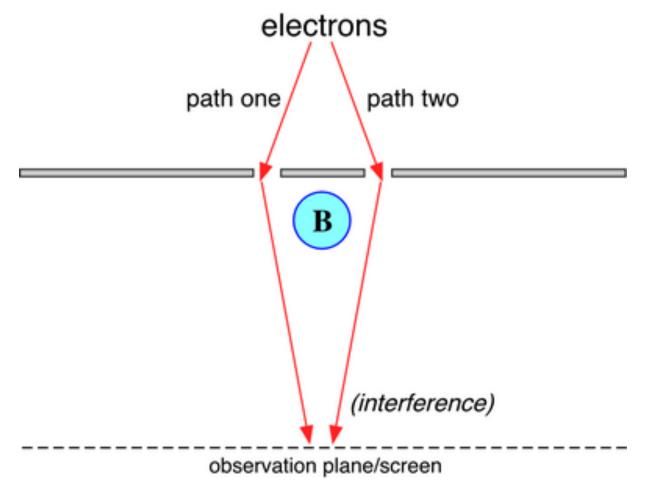


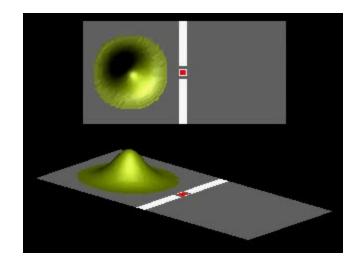
Illustration of interference experiment for Aharonov-Bohm effect

# A-B Effect

Comparison of non-B and B simulations

$$B = 0 = \nabla \times A$$

$$\nabla \times A = B$$



#### A-B Effect

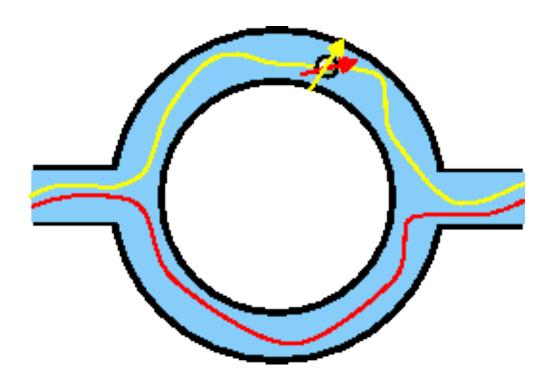
Formulations

$$\phi = \frac{q}{\hbar} \int_{P} A \cdot dx$$

$$\Delta \phi = \frac{q\Phi}{\hbar} \quad \text{(Magnetic A-B Effect)}$$

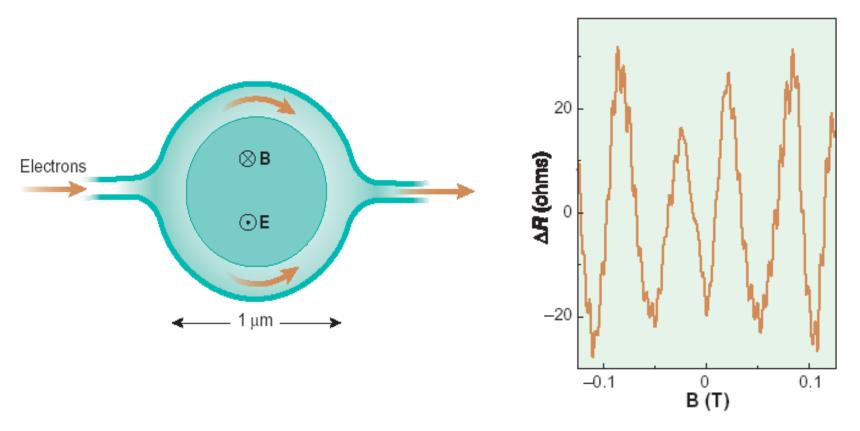
$$\Delta \phi = -\frac{qVt}{\hbar} \quad \text{(Electric A-B Effect)}$$

# Ring Oscillations



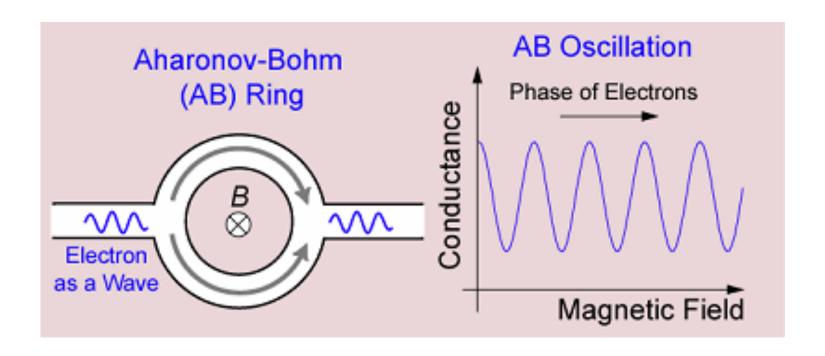
Ring Oscillation without E/B Field

# Ring Oscillations

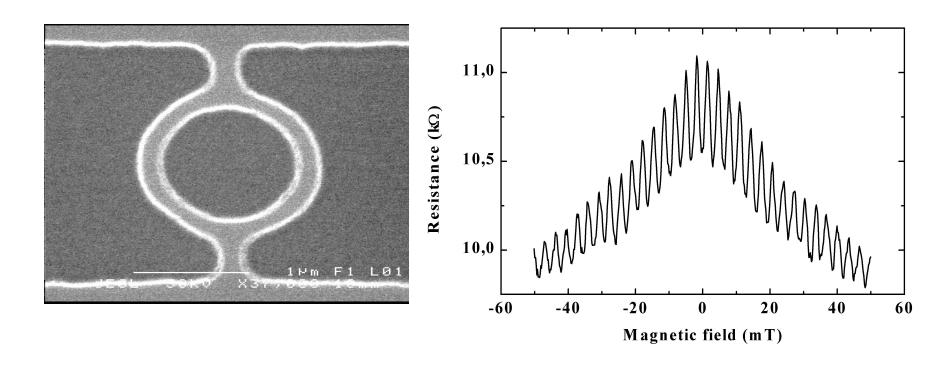


Ring Oscillations with E/B Field

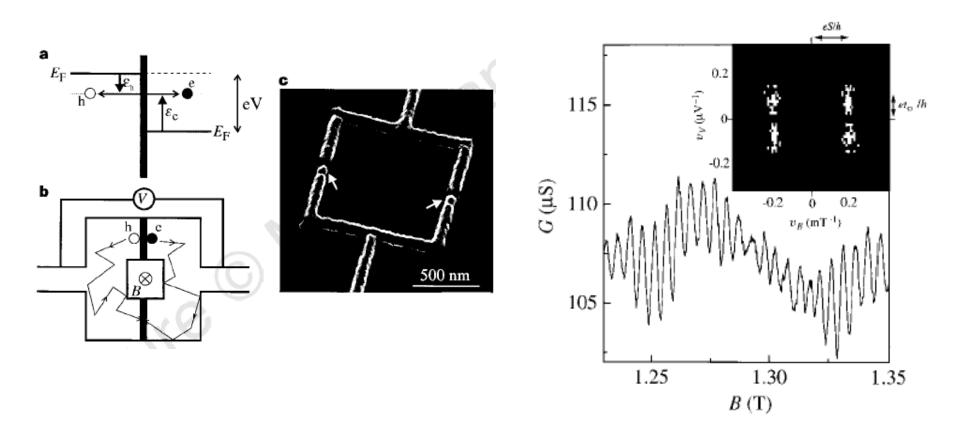
# Ring Oscillation



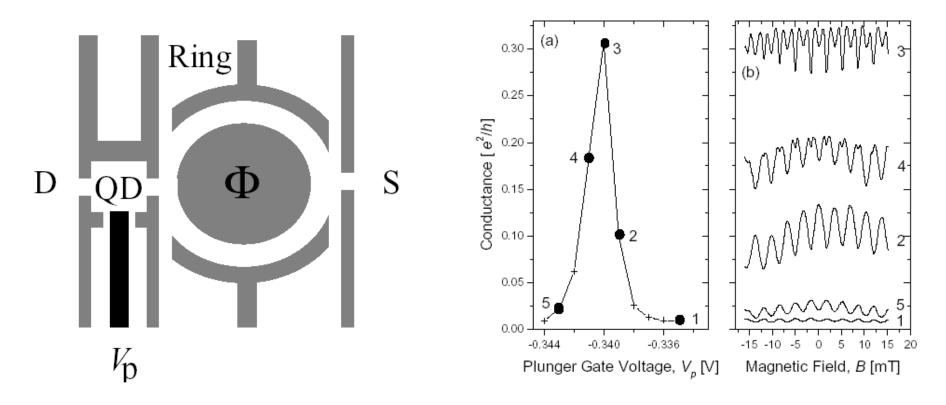
$$\Delta R = \frac{\pi r^2 B}{NWt 2e}$$



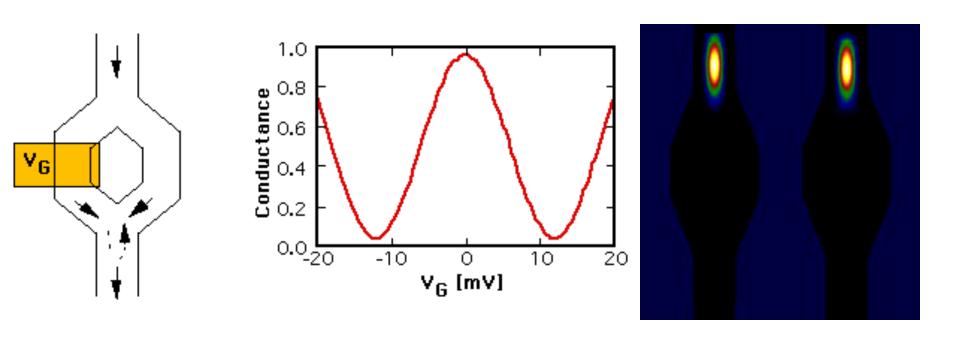
A-B Ring in Semiconductor



A-B Ring in Metal



A-B oscillation in a Ring with a QD connected in series



A-B interferometer